



BOOSTING THE EFFICIENCY
OF COMPOUND SEMICONDUCTOR DEVICES

推进高效率化合物半导体器件技术



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Passivation of compound semiconductors – key enabler for high-efficiency μ LED devices

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CTO, Comptek Solutions

EPIC Online Technology Meeting on Mini/Micro LED

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- **Forerunner in III-V compound semiconductor atomic scale engineering**
- **Founded 2017, office and labs in **Turku, Finland****
- **7000 sq ft labs with ISO 5 cleanroom**
- **Top expertise in **III-V passivation****
- **State-of-the-art process **measurement and characterisation** services**

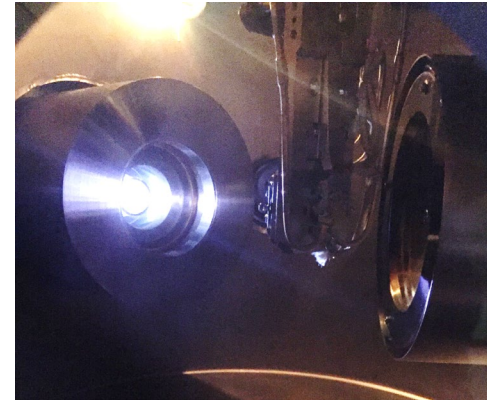
Kontrox™



State-of-the-art process- and characterization capabilities

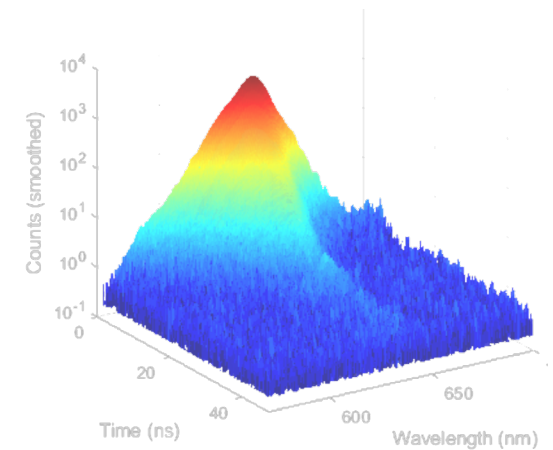
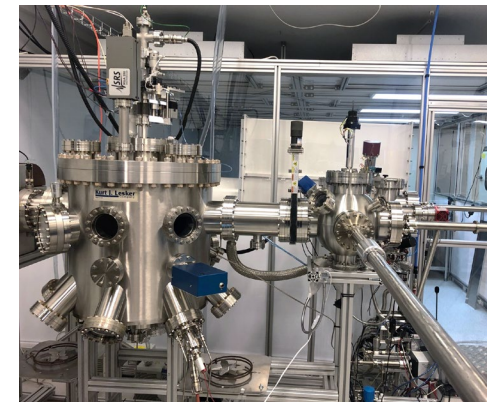
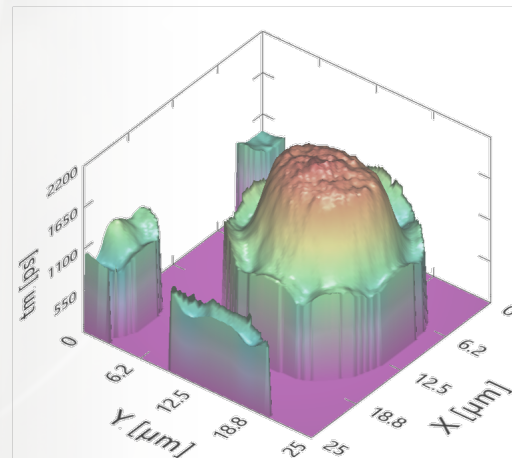


**Customized cleaning
and passivation
techniques**

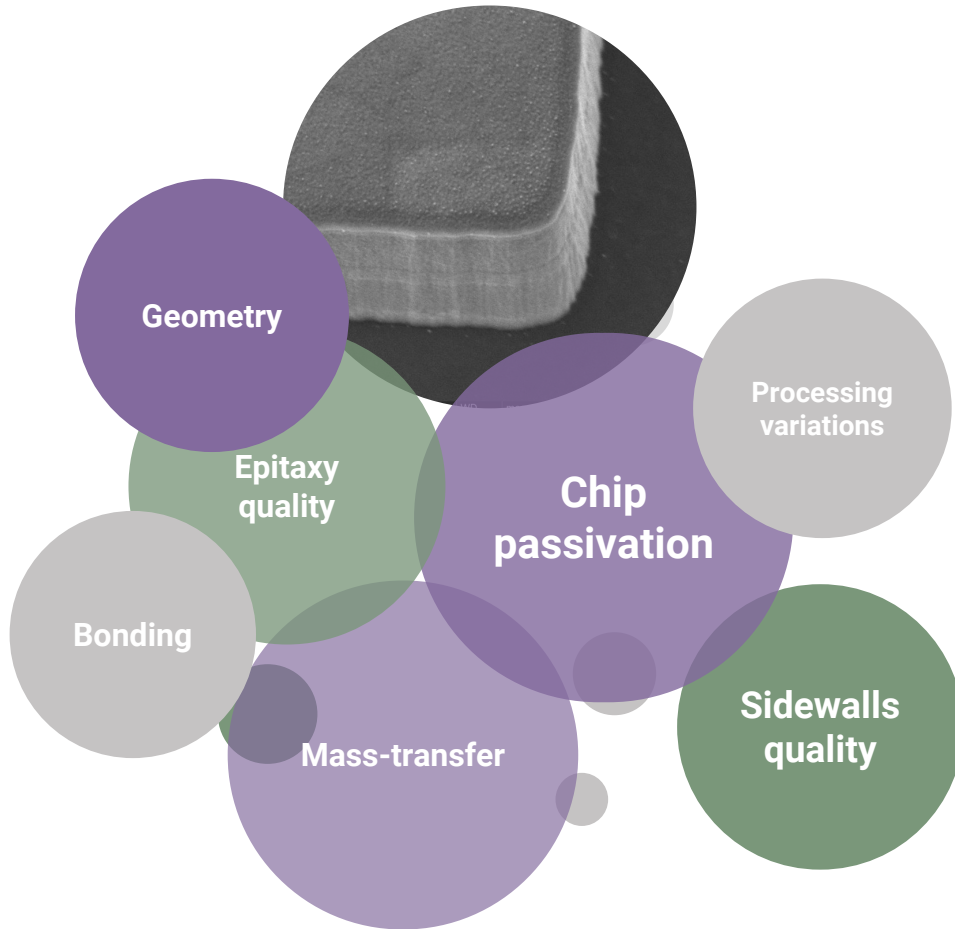


**State-of-the-art
characterization
methods**

(from atomic level to
device)



Challenges in mini/microLEDs:



The smaller the LED, the more influence the defects have in the overall performance

MiniLED and microLEDs sizes ranging from 150 μm down to 1 μm .

The surface/volume ratio increases when chip size is reduced.

The sidewall surface quality and differences arising from the processing steps start to contribute substantially to the overall μLED performance when the chip size decreases.

Principal factors affecting microLED performance

Sidewall damage and oxidation

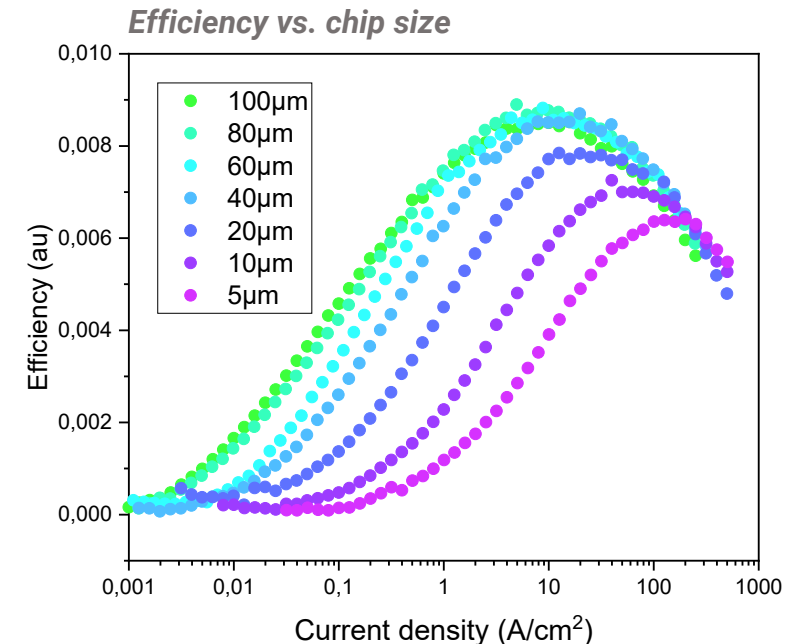
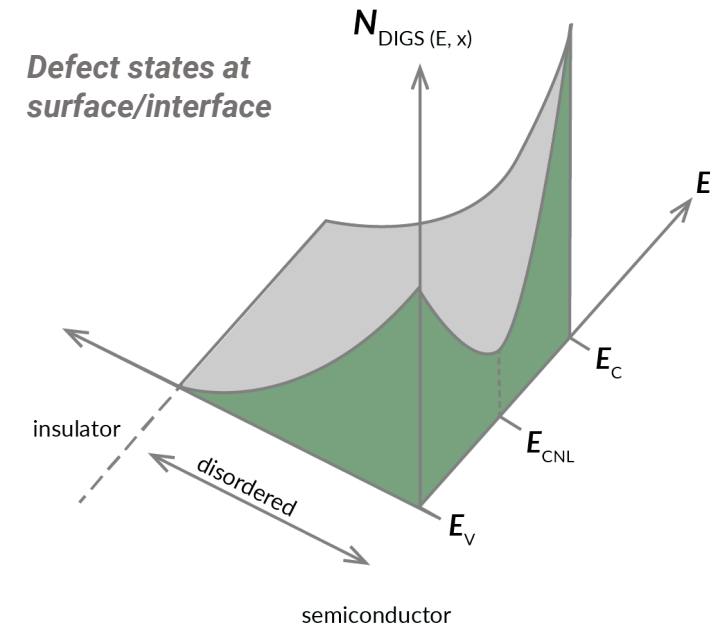
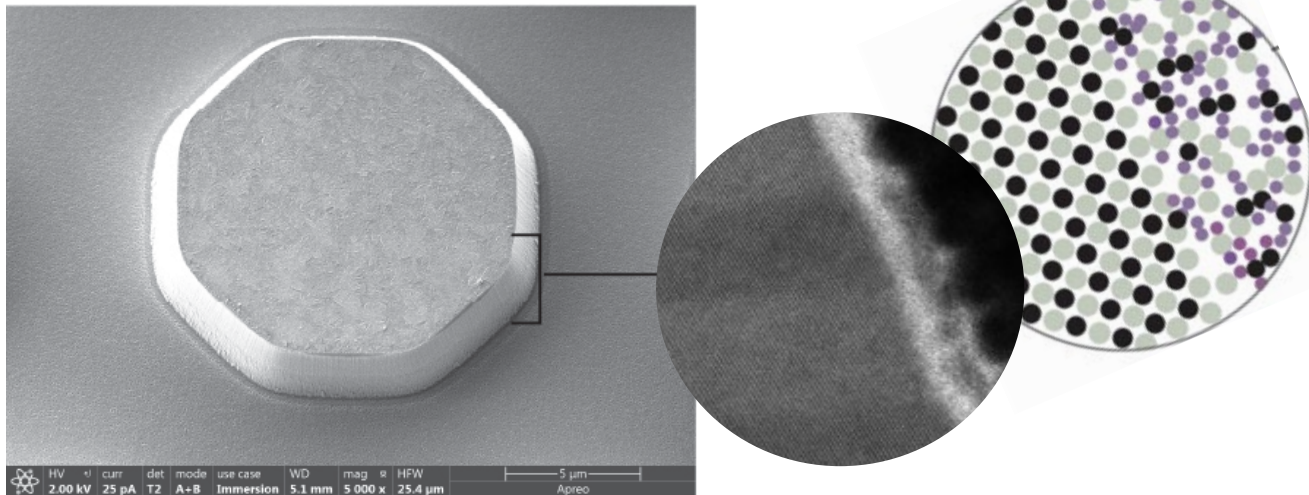
During the chip manufacturing III-V materials easily oxidize generating high density of defects.

Surface/interface defects result in:

- **Performance- and device efficiency losses**
- Increased probability of defective devices causing **lower production yields**.

The negative effect of surface defects becomes more prominent as the chip size gets smaller due to high surface-to-volume ratio.

Native oxide at mesa sidewall



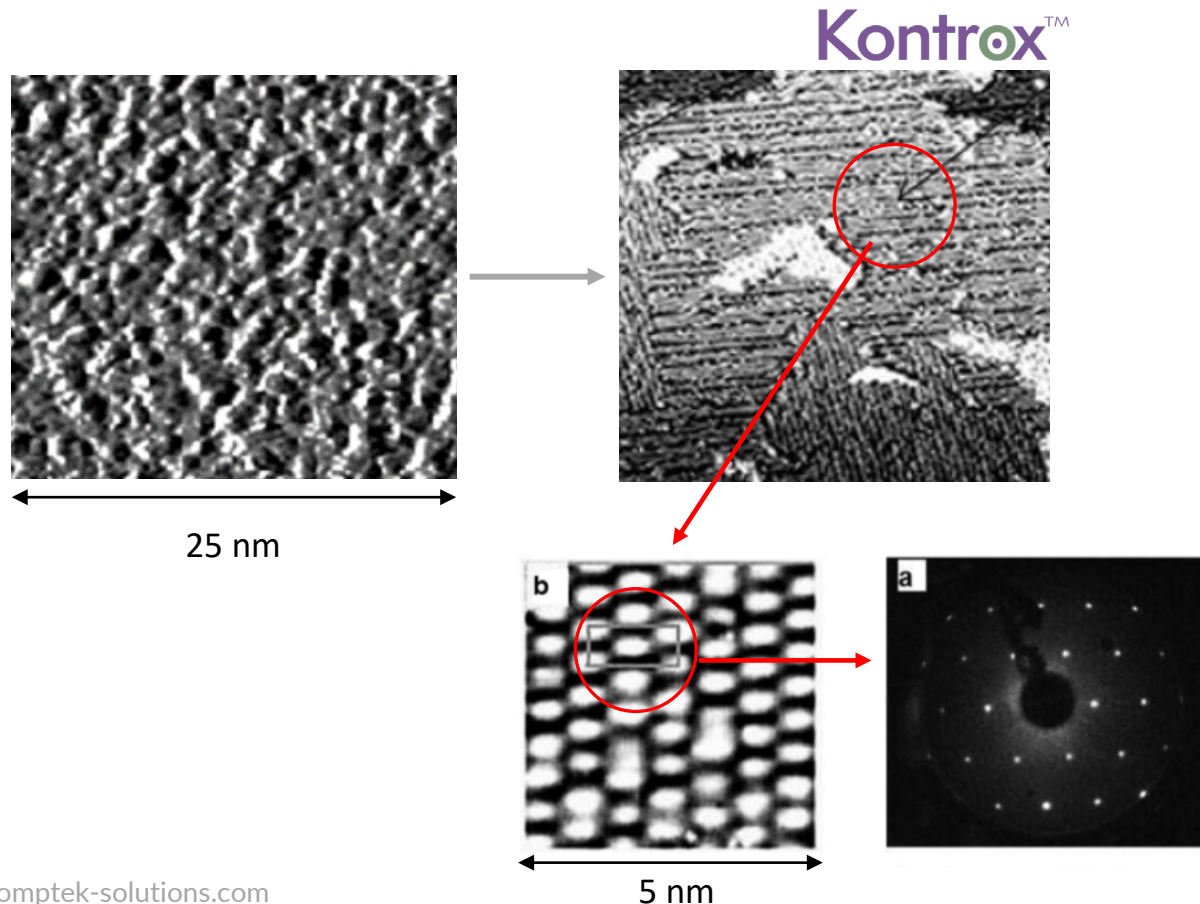
Our solution:



**Achieving up to 98% reduction
of interface defect state density
compared to existing methods**

Outcome:

Kontrox™ transforms the external layer of the materials into perfect **crystalline oxides stable under air exposure**



QUALITY

Perfect crystalline III-V oxide with 98% reduction of defect states

STABILITY

Stable against air exposure and high temperature annealing

PERFORMANCE

Reduced non-radiative recombination, IQE improvement

IMPLEMENTATION

High vacuum, dry and conformable process, applicable to majority of III-V materials



Materials scope:



OPTOELECTRONICS

- Mesa sidewall passivation
- Barrier layer in QW stack
- AR coating passivation
- Protective layer during processing
- Facet passivation

Laser diode	LED	CPV	IR detectors
GaAs	GaN	AlInP	GaAs
AlGaAs	AlGaN	GaInP	InGaAs
InAlGaAs	InGaN	GaAs	InSb
InGaAs	GaAs	InGaAs	InP
InP	AlGaP	AlGaInP	GaSb
GaInP	AlGaInP	AlGaAs	
AlGaInP	GaP		

CMOS

- Key enabler for III-V MOS based transistors for gate dielectric passivation

MOS III-V
InAs
InGaAs
InSb

RADIO FREQUENCY

- Interface passivation layer for MOS-HEMT

p-HEMT
GaAs
AlGaAs
GaInP
InGaAs

m-HEMT
InP
InGaAs
GaInP

POWER ELECTRONICS

GaN
GaN
AlGaN
InGaN



Kontrox for microLEDs

- Optimized and customized processes to enhance chip EQE
- Applicable to GaN (blue and green) and InGaAlP (native red) microLEDs

STEP 1

PREPARATION

Selected processes to achieve an optimal quality for the chip side walls, e.g. ICP damage Healing and Native Oxide removal

STEP 2

PASSIVATION

A very controlled process performed in UHV conditions to form a high-quality oxides on the sidewalls and exposed surfaces of the μ LEDs

STEP 3

OVERCOATING

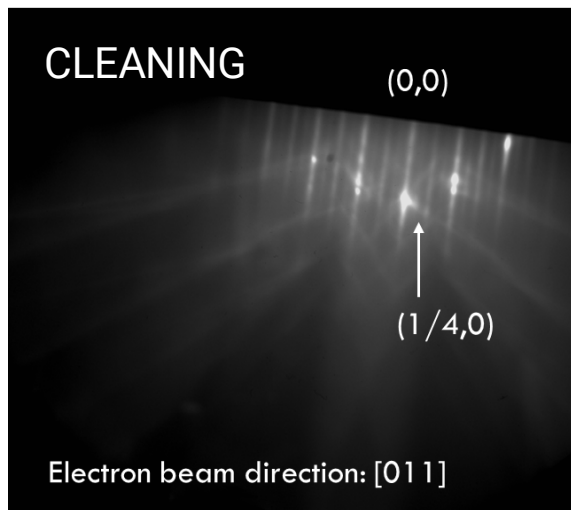
Traditional overcoating on top of Kontrox. - ALD, PECVD, etc. Kontrox ensures defect-free interface between the sidewall and overcoating

Enabling native red

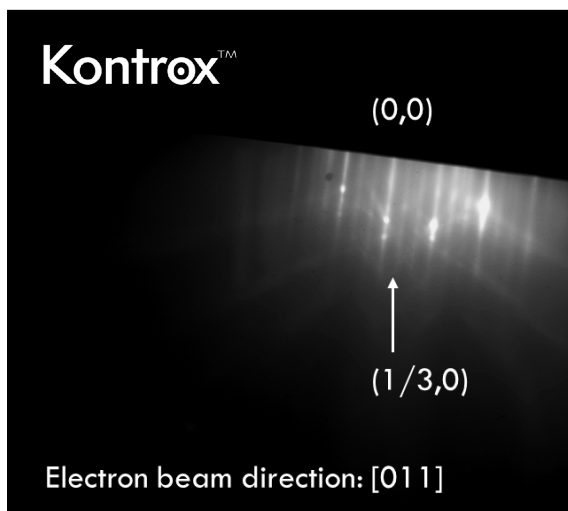


Material-level

Clean InGaAlP(100)(4×2)

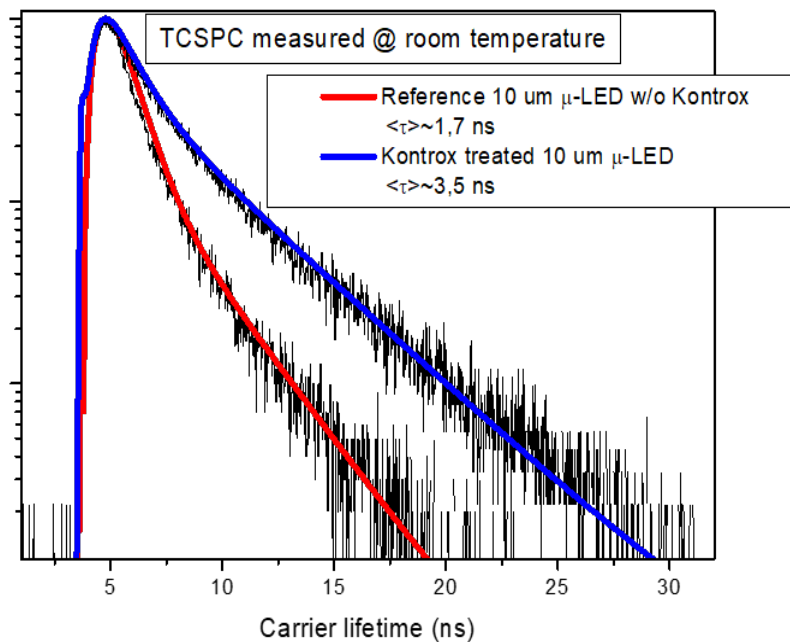


KONTROX InGaAlP(100)(3×1)

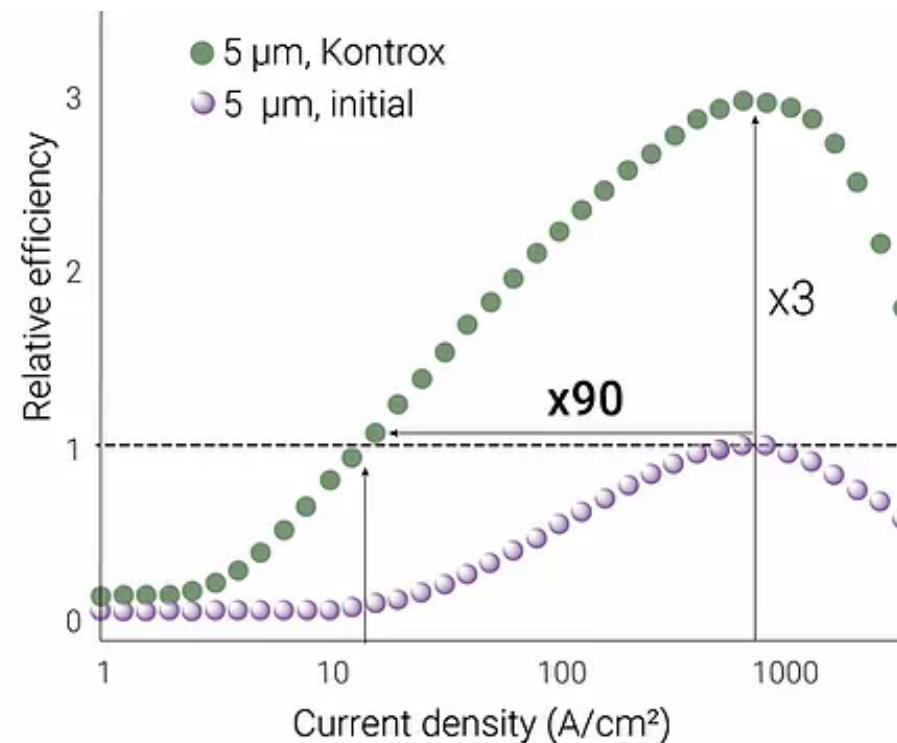


Mesa-level

Lifetime decay curve

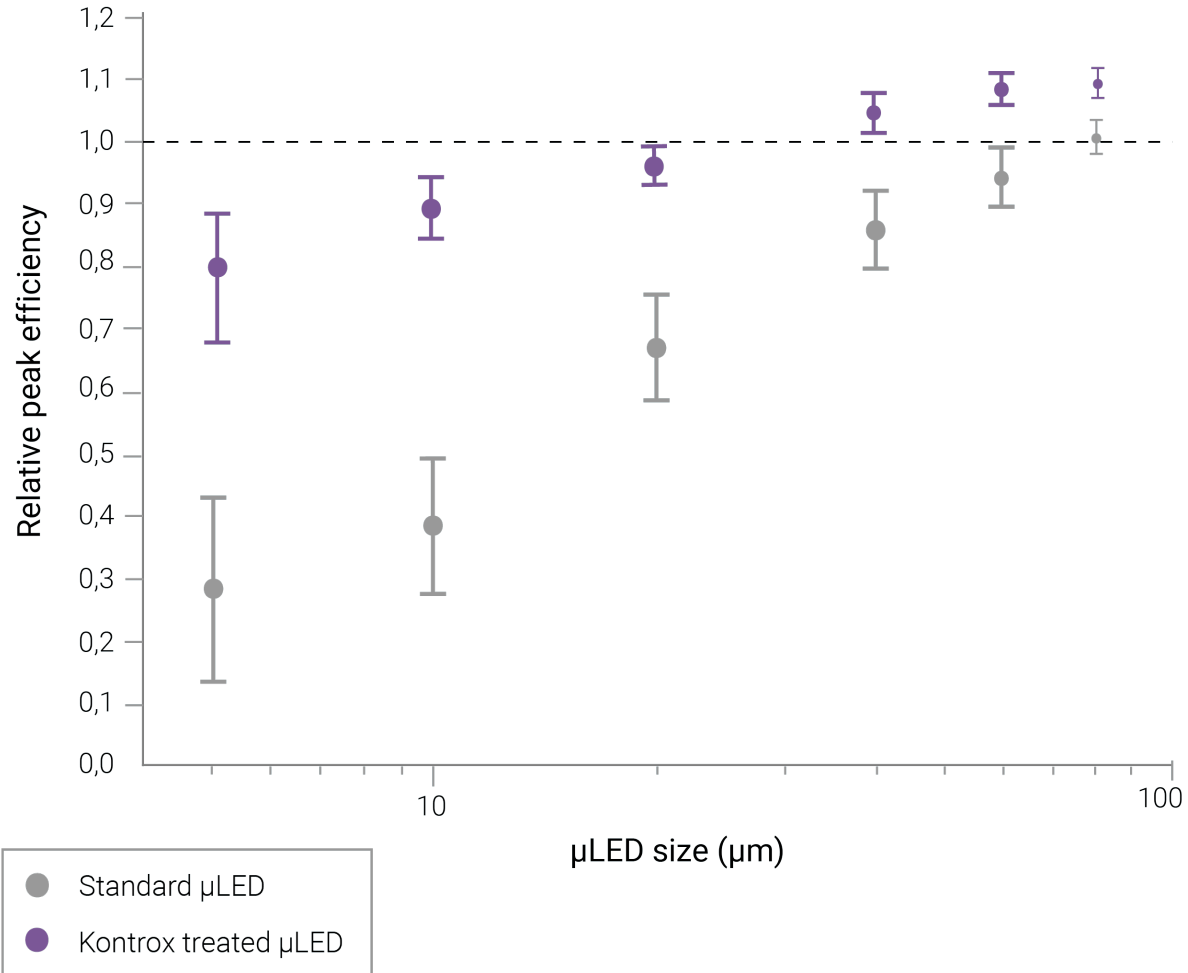


μ LED-level

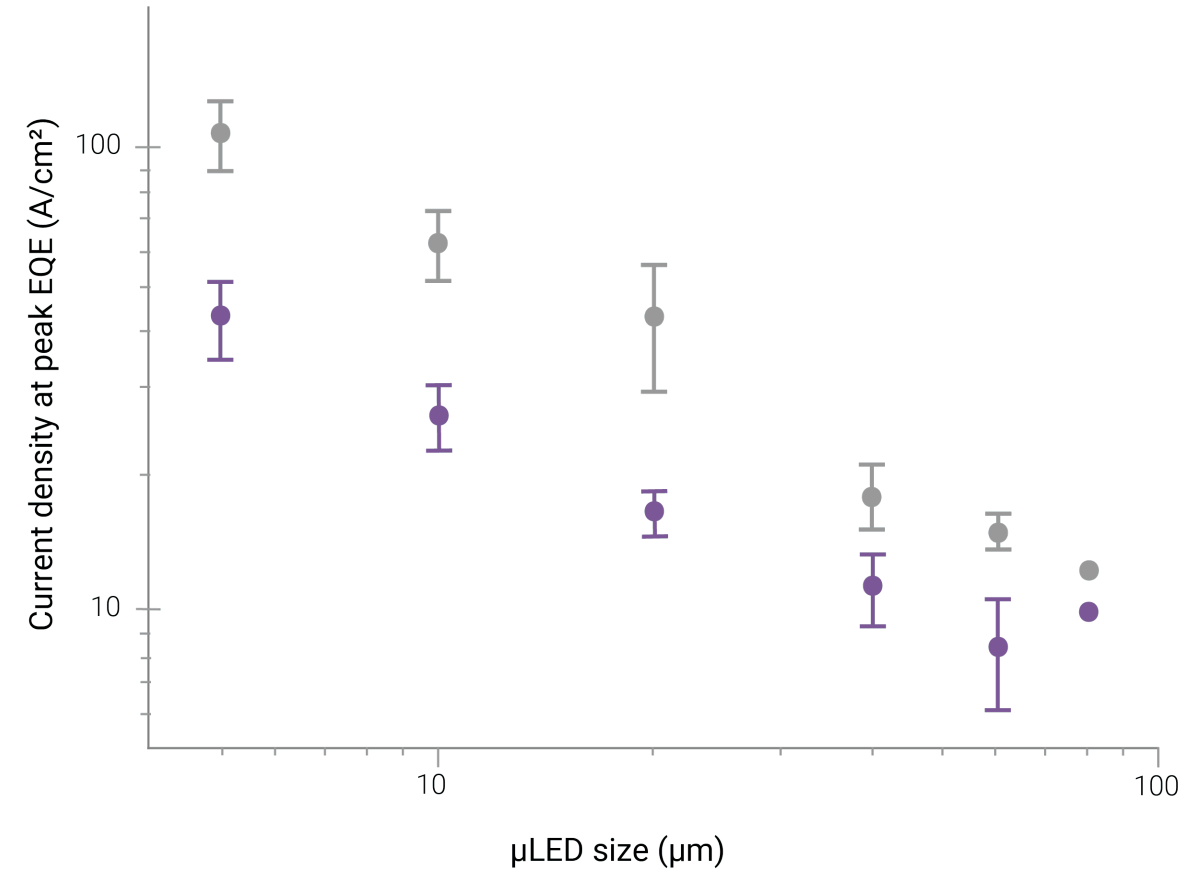




Relative size dependent peak EQE vs. standard 80μm μLED



Current density @ peak EQE





Added value for microLED:

HIGHER EQE FOR MAXIMUM DISPLAY BRIGHTNESS

EQE improvements of
**40% for blue chips and
up to 250% for red
chips**

LESS POWER CONSUMPTION

**Up to 100 times lower
current density vs
untreated sample**

ENABLING NATIVE RGB

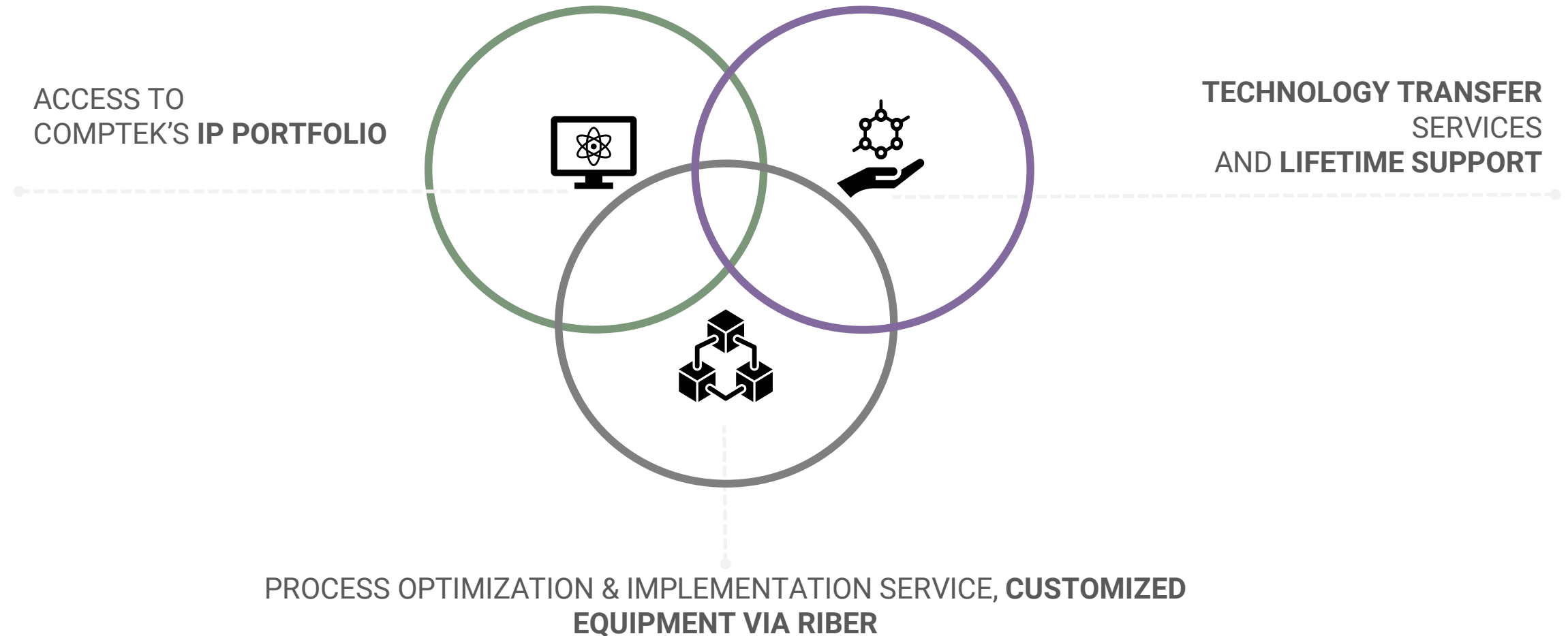
Kontrox™ is the **most
effective technology to
improve the efficiency
on InGaAlP based
devices.**

INCREASED MANUFACTURING YIELD

Kontrox™ improves the
uniformity between chips
reducing binning
activities



Turn-key technology implementation solutions





IN SEARCH OF IMPROVED PERFORMANCE FOR OPTOELECTRONIC DEVICES?

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